



UF50N06-Q

Preliminary

Power MOSFET

50A, 60V N-CHANNEL POWER MOSFET

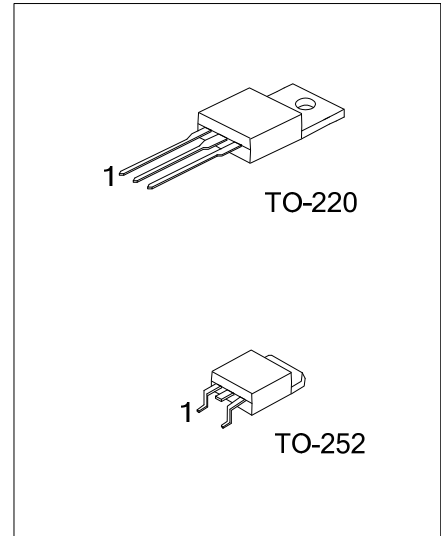
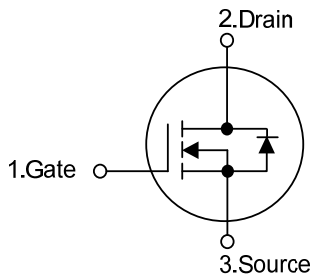
DESCRIPTION

The UTC **UF50N06-Q** is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(ON)} < 25m\Omega @ V_{GS}=10V, I_D=25A$
- * High switching speed
- * 100% avalanche tested

SYMBOL



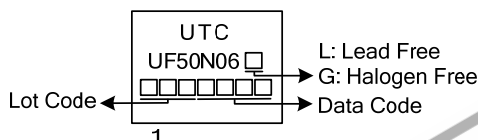
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
UF50N06L-TA3-T	UF50N06G-TA3-T	TO-220	G	D	S	Tube
UF50N06L-TN3-R	UF50N06G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>UF50N06G-TA3-T</p> <p>(1)Packing Type (2)Package Type (3)Green Package</p>	<p>(1) T: Tube, R: Tape Reel (2) TA3: TO-220, TN3: TO-252 (3) G: Halogen Free and Lead Free L: Lead Free</p>
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MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	60	V
Gate-Source Voltage		V_{GSS}	± 25	V
Continuous Drain Current	Continuous	I_D	50	A
	Pulsed	I_{DM}	200	A
Avalanche Energy		E_{AS}	287	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	12.6	V/ns
Power Dissipation	TO-220	P_D	80	mW
	TO-252		50	mW
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature Range		T_{STG}	-55 ~ +150	$^\circ\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=0.38\text{mH}$, $I_{AS}=38\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\ \Omega$, Starting $T_J = 25^\circ\text{C}$

4. $I_{SD} \leq 50\text{A}$, $di/dt \leq 250\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220	θ_{JA}	62.5	$^\circ\text{C}/\text{W}$
	TO-252		110	$^\circ\text{C}/\text{W}$
Junction to Case	TO-220	θ_{JC}	1.56	$^\circ\text{C}/\text{W}$
	TO-252		2.5	$^\circ\text{C}/\text{W}$

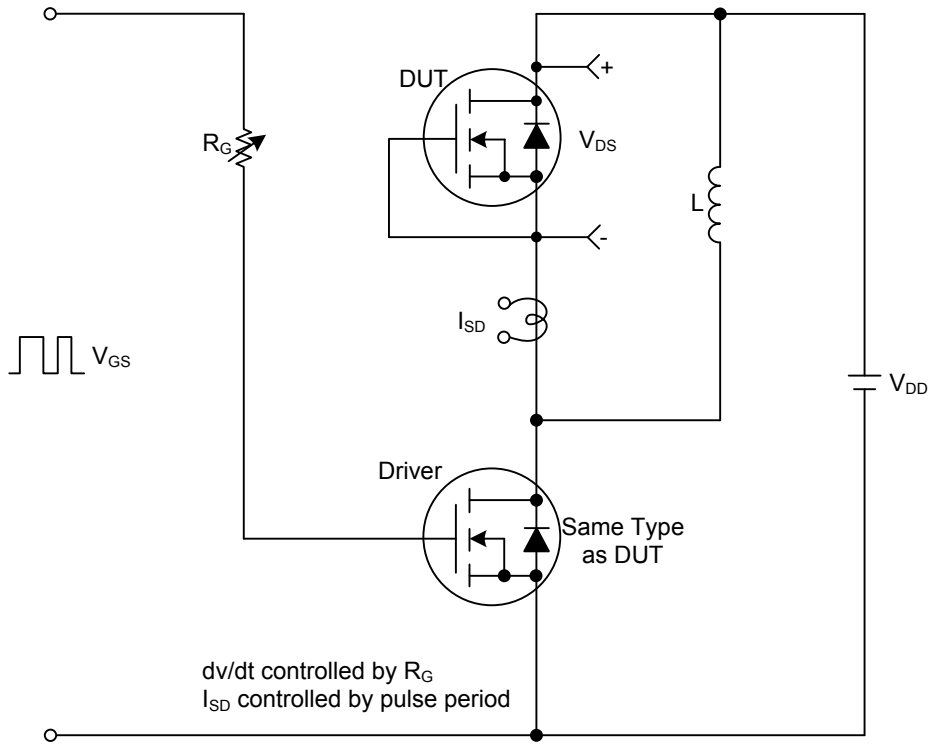
■ ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	60			V
Drain-Source Leakage Current	I_{DSS}	$V_{DS} = 60\text{V}$, $V_{GS} = 0\text{V}$			1	μA
Gate-Source Leakage Current	Forward	$V_{GS} = +20\text{V}$, $V_{DS} = 0\text{V}$			10	μA
	Reverse		$V_{GS} = -20\text{V}$, $V_{DS} = 0\text{V}$			-10
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$I_D = 250\mu\text{A}$, $V_{DS} = V_{GS}$	2.0		4.0	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS} = 10\text{V}$, $I_D = 25\text{A}$			25	m Ω
DYNAMIC PARAMETERS						
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$		1800		pF
Output Capacitance	C_{OSS}			390		pF
Reverse Transfer Capacitance	C_{RSS}			64		pF
SWITCHING PARAMETERS						
Total Gate Charge (Note 1)	Q_G	$V_{GS} = 10\text{V}$, $V_{DS} = 50\text{V}$, $I_D = 1.3\text{A}$ $I_G = 100\mu\text{A}$ (Note 1, 2)		63.6		nC
Gate to Source Charge	Q_{GS}			9.2		nC
Gate to Drain Charge	Q_{GD}			12		nC
Turn-ON Delay Time (Note 1)	$t_{D(ON)}$	$V_{GS} = 10\text{V}$, $V_{DD} = 30\text{V}$, $R_G = 25\Omega$, $I_D = 0.5\text{A}$ (Note 1, 2)		78		ns
Rise Time	t_R			81		ns
Turn-OFF Delay Time	$t_{D(OFF)}$			340		ns
Fall-Time	t_F			162		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I_S				50	A
Maximum Body-Diode Pulsed Current	I_{SM}				200	A
Drain-Source Diode Forward Voltage (Note 1)	V_{SD}	$I_S = 20\text{A}$, $V_{GS} = 0\text{V}$			1.4	V
Body Diode Reverse Recovery Time (Note 1)	t_{rr}	$I_S = 40\text{A}$, $V_{GS} = 0\text{V}$		66		ns
Body Diode Reverse Recovery Charge	Q_{rr}	$dI_F/dt = 100\text{A}/\mu\text{s}$		0.5		μC

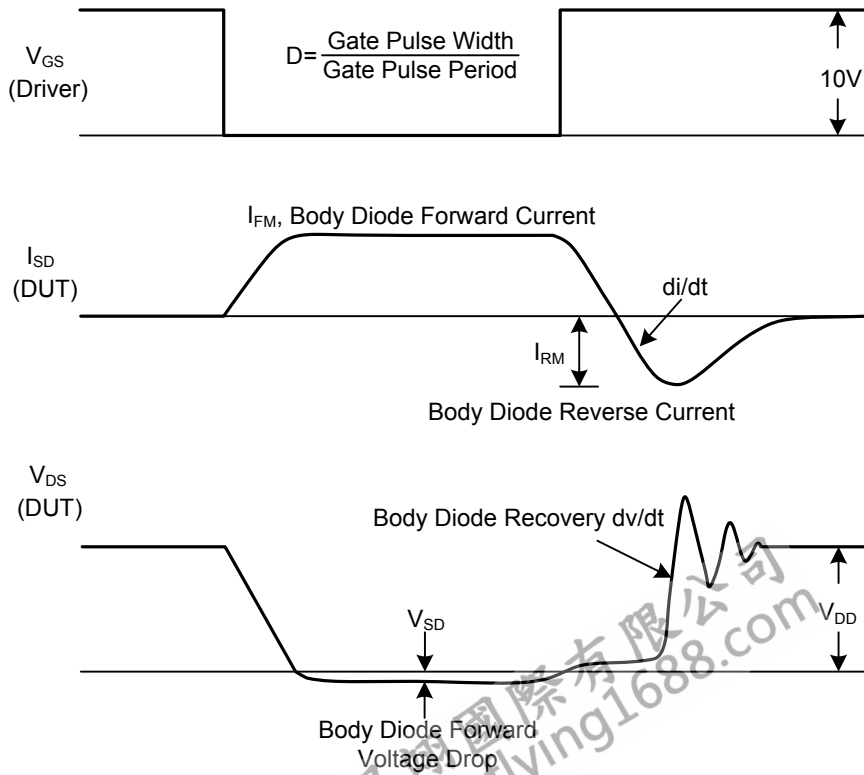
Notes: 1. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

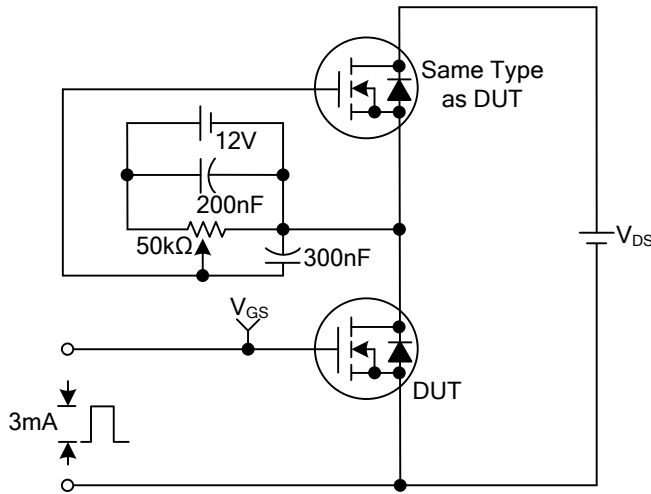


Peak Diode Recovery dv/dt Test Circuit

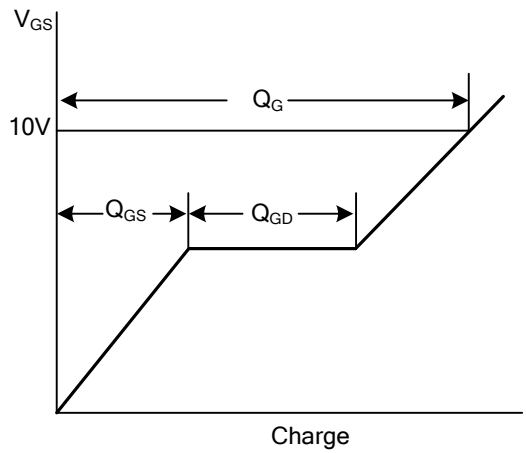


Peak Diode Recovery dv/dt Waveforms

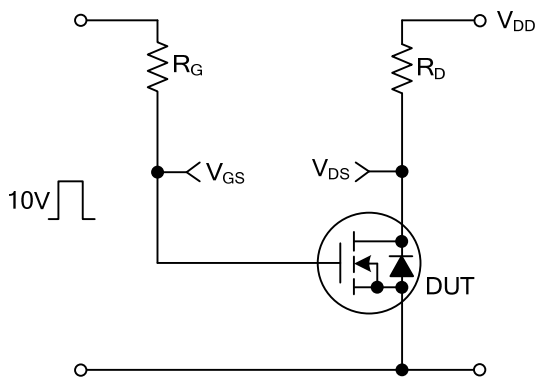
■ TEST CIRCUITS AND WAVEFORMS



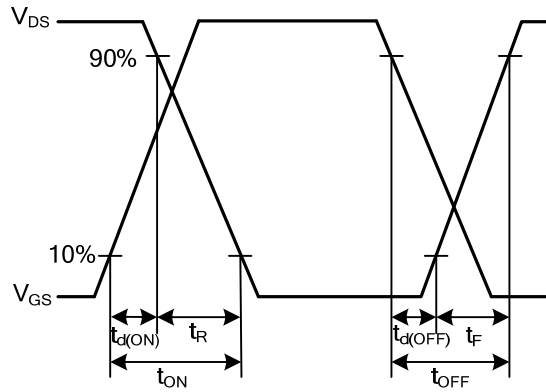
Gate Charge Test Circuit



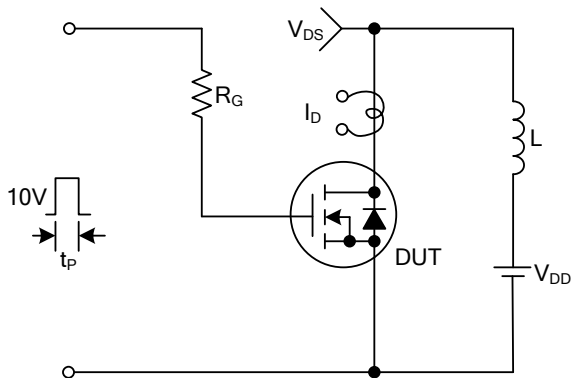
Gate Charge Waveforms



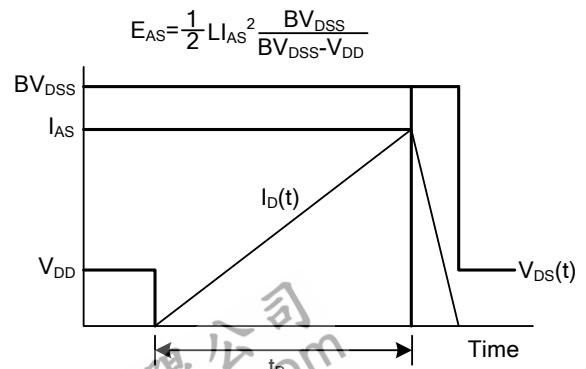
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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